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Report No. 240801086GZU-001

TEST REPORT IEEE 1547

IEEE Standard for Interconnecting Distributed Resources with Electric Power Systems

Report Number.....: 240801086GZU-001

Date of issue: 03 Sep., 2024

Total number of pages 46 pages

Name of Testing Laboratory Intertek Testing Services Shenzhen Ltd. Guangzhou Branch

Caipin Road, Huangpu District, Guangzhou, Guangdong, China

Applicant's name Huawei Technologies Co., Ltd.

Address Administration Building, Headquarters of Huawei Technologies Co.,

Ltd., Bantian, Longgang District, Shenzhen, 518129, P.R.C

Test specification:

Standard: IEEE 1547: 2003, IEEE 1547a:2014 & IEEE 1547.1: 2005+ A1:

2015

Test procedure....:: Type approval

Condition of the item tested : Prototype

Non-standard test method.....: N/A

Test Report Form No...... IEEE1547_a

Test Report Form(s) Originator....: Intertek Testing Services Shenzhen Ltd. Guangzhou Branch

Master TRF Dated 2021-04

General disclaimer:

The test results presented in this report relate only to the object tested.

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Test item description....:: Solar Inverter

Trade Mark....::

HUAWEI

Manufacturer: Same as applicant

Model/Type reference.....: SUN2000-50K-MGL0, SUN2000-50K-MGL0-BR, SUN2000-75K-MGL0-BR,

SUN2000-80K-MGL0

Ratings....::

Model	SUN2000-50K-MGL0	SUN2000-50K-MGL0- BR				
Max. Input voltage	750Vdc					
MPPT voltage range	160 ~ 7	750Vdc				
Max. input current	48A	dc*7				
Max. Isc	66A	dc*7				
Rated output power	50kW	50kW				
Max. Output Apparent power	55kVA	55kVA				
Nominal output voltage	3/N/PE 12	7/220 Vac				
Nominal output current	131.3Aac	131.3Aac				
Max. output current	144.4Aac	144.4Aac				
Nominal output frequency	60Hz					
Power factor range	0.8(Leading) ~ 0.8(Lagging)					
Ingress protection	IP66					
Operation ambient temperature	-25°C to +60°C					
Software version	SUN2000MG_	V600R023C10				
Model	SUN2000-75K-MGL0- BR	SUN2000-80K-MGL0				
Max. Input voltage	750	Vdc				
MPPT voltage range	160 ~ 7	750Vdc				
Max. input current	48A	dc*7				
Max. Isc	66A	dc*7				
Rated output power	75kW	80kW				
Max. Output Apparent power	75kVA	88kVA				
Nominal output voltage	3/N/PE 12	27/220Vac				



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	Nominal output current	196.9Aac	210.0Aac	
	Max. output current	196.9Aac	231.0Aac	
	Nominal output frequency	60	Hz	
	Power factor range	0.8(Leading) -	- 0.8(Lagging)	
	Ingress protection	IP	P66 to +60°C	
	Operation ambient temperature	-25°C to		
Software version SUN2000MG_V600R023		V600R023C10		



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Resp	Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):							
\boxtimes	Testing Laboratory:	Intertek Testing Service Branch	Intertek Testing Services Shenzhen Ltd. Guangzhou Branch					
Test	ing location/ address::		202/302/402/502/602/702/802, No. gpu District, Guangzhou,					
	Associated CB Testing Laboratory:	N/A						
Test	ing location/ address:	N/A						
Test	ed by (name, function, signature):	Luther Qiu	Lither Di					
		Engineer	Lumor aru					
App	oved by (name, function, signature):	Jason Fu	Luther Qiu Dason Tu					
		Supervisor	Jasen 100					
	Testing procedure: CTF Stage 1:	N/A						
Test	ing location/ address:	N/A						
Test	ed by (name, function, signature):	N/A						
App	oved by (name, function, signature):	N/A						
	Testing procedure: CTF Stage 2:	N/A						
Test	ing location/ address:	N/A						
Test	ed by (name + signature):	N/A						
Witn	essed by (name, function, signature).:	N/A						
App	oved by (name, function, signature):	N/A						
	Testing procedure: CTF Stage 3:	N/A						
	Testing procedure: CTF Stage 4:	N/A						
Test	ing location/ address:	N/A						
Test	ed by (name, function, signature):	N/A						
Witn	essed by (name, function, signature).:	N/A						
App	oved by (name, function, signature):	N/A						
Supe	ervised by (name, function, signature) :	N/A						





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List of Attachments (including a total number of pages in each attachment): N/A							
Summary of testing:							
Tests performed (name of test and test	Testing location:						
clause): All applicable tests	Intertek Testing Services Shenzhen Ltd. Guangzhou Branch						
	Room101/301/401/102/202/302/402/502/602/702/80 2, No. 7-2, Caipin Road, Huangpu District, Guangzhou, Guangdong, China						
Summary of compliance with National Differences (List of countries addressed): N/A							
☐ The product fulfils the requirements of IEEE 1	1547: 2003 & IEEE 1547.1: 2005+ A1: 2015						



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Copy of marking plate:

The artwork below may be only a draft. The use of certification marks on a product must be authorized by the respective NCBs that own these marks.

扫码获取支持



型号 Model: SUN2000-50K-MGL0 名称 Name: 太阳能光伏逆变器 SOLAR INVERTER

通讯方式 Communication: MBUS/RS485 电弧故障保护 AFCI: TYPE I



Modelo: SUN2000-50K-MGL0-BR INVERSOR SOLAR

Tensão c.c. máxima: 750 V Faixa de operação do SPMP: 160 - 750 V Corrrente de curto circuito (por entrada): 7xt Corrente c.c. máxima (por entrada): 7x48 A Tensão c.a. nominal: 127/220 V Tensão c.a. nominal: 127/220 V Frequência nominal: 50/60 Hz Potência c.a. nominal: 50 kW Potência aparente nominal: 55 kVA Corrente de saída nominal: 31.3 A Potência aparente máxima: 55 kVA Corrente c.a. máxima fornecida: 144.4 A Corrente c.a. máxima fornecida: 144.4 A
Fator de potência: 0.8(atrasado) - 0.8 (adiantado)
Faixa de temperatura de operação: - 25 - + 60°C
Categoria de sobretena5a: (Ic.o.;III(c.a.)
Topologia do inversor. Não isolado
Grau de proteção (IP): IP66
Nível de proteção: 1
Sistema de proteção de acros elétricos em série
("Interrupção de Arco")
Atenção: verificar no manual do equipamento a for

(interrupção de Arco) Atenção: verificar no manual do equipamento a forma adequada de realizar a instalação elétrica e se há necessidade de dispositivos de proteções elétrica

HUAWEI TECHNOLOGIES CO., LTD.



华为技术有限公司 HUAWEI TECHNOLOGIES CO., LTD.



HQ of Huawei, Bantian, Longgang District, Shenzhen, 518129, P.R.C

Modelo: SUN2000-75K-MGL0-BR

INVERSOR SOLAR

HUAWEI

Tensão c.c. máxima: 750 V

Faixa de operação do SPMP: 160 - 750 V

Corrente de curto circuito (por entrada): 7x66 A

Corrente c.c. máxima (por entrada): 7x48 A

Tensão c.a. nominal: 127220 V

Frequência nominal: 50/60 Hz

Potência aparente nominal: 75 kW

Potência aparente nominal: 75 kW

Potência aparente máxima: 75 kVA

Corrente de saída nominal: 196.9 A

Fator de potência: 0.8(arsado) - 0.8 (adiantado)

Faixa de temperatura de operação: -25 - + 60°C

Categoria de sobretensão: II(c.c.)/III(c.a.)

Topologia do inversor: Não isolado

Grau de proteção (IP): IP66

Nivel de proteção: IP): IP66

Nivel de proteção de arcos'

Atenção: verificar no manual do equipamento a forma adequada de realizar a instalação elétrica e se há necessidade de dispositivos de proteções elétrica

essidade de dispositivos de proteções elétrica

型号 Model: SUN2000-80K-M 名称 Name: 太阳能光伏逆变器 HUAWEI SOLAR INVERTER

型号 Model: SUN2000-80K-MGL0

HUAWEI SULAR INVERTER

最大輸入电压 d.c.Max.Input Voltage: 750 Vd.c.
最大輸入电流 d.c.Max.Input Current: 7×48 A
輸入短路电流 lsc: 7×68 A
輸入短路电流 lsc: 7×68 A
MPPT BLE 50 B d.c.MPPT Range: 160 − 750 Vd.c.
輸出电压 a.c.Output Nominal Voltage: 1277220 Va.c; 3(N) ~ + 争 輸出电压 a.c.Cutput Rated Power: 88 kW(cospe=1) 最大規定力率 a.c.Max.Output Power: 88 kW(cospe=1) 最大規定力率 a.c.Output Max.Current: 231.0 A; 220 Va.c.
功率因数 Power Factor: 0.8(lagging) − 0.8(leading) 温度范围 Dperating Temperature Range: −25 − +60 °C 速变器排扑 Inverter Topology: Non − Isolation 防护等级 Enclosure: IP66 保护等级 Protection Class: 1 过程正类别 Overvoltage Category: II(DC)III(AC) 污染等级 Pollution Degree: III 温讯方式 Communication: MBUS/RS485 电弧粒棒探护 AFCI: TYPE I

HQ of Huawei, Bantian, Longgang District, Shenzhen, 518129, P.R.C

通讯方式 Communication: M 电弧故障保护 AFCI: TYPE I



合格证 QC PASS

扫码获取支持 Scan for support



HUAWEI TECHNOLOGIES CO., LTD. HQ of Huawei, Bantian, Longgang District, Shenzhen, 518129, P.R.C 华为技术有限公司 HUAWEI TECHNOLOGIES CO., LTD. 中国制造 N HQ of Huawei, Bantian, Longgang District, Shenzhen, 518129, P.R.C

Note:

- The above markings are the minimum requirements required by the safety standard. For the final production samples, the additional markings which do not give rise to misunderstanding may be added.
- Label is attached on the side surface of enclosure and visible after installation.



Total Quality. Assured. Page 7 of 46 Report No. 240801086GZU-001 Test item particulars....:: hand-held stationary ☐ transportable for building-in ⊠ fixed direct plug-in permanent connection for building-in Environmental category....:: 🛛 outdoor indoor unconditional conditional Over voltage category Mains:: OVC I **⊠** OVC III OVC IV Over voltage category DC:: OVC I ⊠ OVC II □ ovc iv Mains supply tolerance (%): -90 / +110 % Tested for power systems: TN systems IT testing, phase-phase voltage (V).....:: : - - -Class of equipment....:: X Class I ☐ Class II Class III ■ Not classified Mass of equipment (kg): Approx. 98kg Pollution degree: Outside PD3; Inside PD2 IP protection class: IP 66 . Possible test case verdicts: - test case does not apply to the test object: N/A - test object does meet the requirement.....: P (Pass) - test object was not evaluated for the requirement: - test object does not meet the requirement.....: F (Fail) Testing....::

Date of receipt of test item: 01 Aug 2024

Date (s) of performance of tests 02 Aug 2024 ~ 02 Sep 2024



General remarks:

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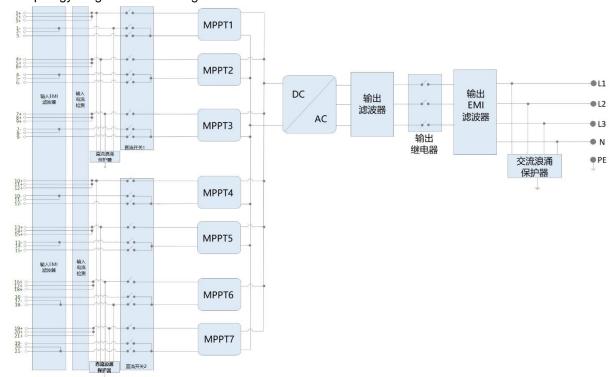
"(See Enclosure #)" refers to additional information appended to the report. "(See appended table)" refers to a table appended to the report.						
Throughout this report a ☐ comma / ☒ point is u	sed as the decimal separator.					
Manufacturer's Declaration per sub-clause 4.2.5 of	IECEE 02:					
The application for obtaining a CB Test Certificate	☐ Yes					
includes more than one factory location and a declaration from the Manufacturer stating that the sample(s) submitted for evaluation is (are) representative of the products from each factory has been provided	⊠ Not applicable					
When differences exist; they shall be identified in t	he General product information section.					
Name and address of factory (ies):	Dongguan Luxshare Smart-Link Electronic Technology Co., Ltd.					
	Building 2, No.313, Qingxi North Ring Road, Qingxi Town, Dongguan City, Guangdong Province, P.R. China.					



General product information:

The Solar Inverter is a three-phase type (without isolating transformer inside) which converts direct current optimized by photovoltaic DC conditioner to alternating current, and they are intended to be connected in parallel with the public grid via an external isolated transformer depend on the rated output voltage of inverter. The winding ratio is adapted according to the voltage level of inverter output and connection point at public grid. They are intended for professional incorporation into PV system, and they are assessed on a component test basis.

The topology diagram as following:



Model difference:

All models of the same series have identical mechanical and electrical construction except some parameter of the software architecture to control the max output power.

SUN2000-50K-MGL0 and SUN2000-50K-MGL0-BR are differentiated between sales territories.

The product was tested on:

The Software version: SUN2000MG_V600R023C10 The Hardware version: SUN2000MG V600R023C10

Other than special notes, the model of SUN2000-80K-MGL0 is type tested.

The reference impedance: Z_source = 1,05 + j 0,32 ohm, I_SC = 210 A



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		IEEE1547		
Clause	Requirement – Test		Result – Remark	Verdict

4.1	General requirements					
4.1.1	Voltage regulation		Р			
	Coordination with and approval of, the area EPS and DR operators, shall be required for the DR to actively participate to regulate the voltage by changes of real and reactive power. The DR shall not cause the Area EPS service voltage at other Local EPSs to go outside the requirements of ANSI C84.1-2011	This unit is local electric power system (Local EPS). The unit is complied with specified ANSI C84.1.	P			
4.1.2	1995, Range A.		N/A			
4.1.2	Integration with Area EPS grounding The grounding scheme of the DR interconnection shall not cause overvoltages that exceed the rating of the equipment connected to the Area EPS and shall not disrupt the coordination of the ground fault protection on the Area EPS.	No DR interconnection.	N/A			
4.1.3	Synchronization		Р			
	The DR unit shall parallel with the Area EPS without causing a voltage fluctuation at the PCC greater than ±5% of the prevailing voltage level of the Area EPS at the PCC, and meet the flicker requirements of 4.3.2.		Р			
4.1.4	Distributed resources on distribution secondary grid and spot networks					
4.1.4.1	Distribution secondary grid networks					
	This topic is under consideration for future revisions of this standard.		N/A			
4.1.4.2	Distribution secondary spot networks					
	Network protectors shall not be used to separate, switch, serve as breaker failure backup or in any manner isolate a network or network primary feeder to which DR is connected from the remainder of the Area EPS,unless the protectors are rated and t ested per applicable standards for such an application.	The unit does not included reclosing of any network protectors installed on the spot network.	N/A			
	Any DR installation connected to a spot network shall not cause operation or prevent reclosing of any network protectors installed on the spot network. This coordination shall be accomplished without requiring any changes to prevailing network protector clearing time practices of the Area EPS.		N/A			
	Connection of the DR to the Area EPS is only permitted if the Area EPS network bus is already energized by more than 50% of the installed network protectors.		N/A			
	The DR output shall not cause any cycling of network protectors.		N/A			
	The network equipment loading and fault interrupting capacity shall not be exceeded with the addition of DR.		N/A			
	DR installations on a spot network, using an automatic transfer scheme in which load is transferred between the DR and the EPS in a		N/A			



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	IEEE1547		
Clause	Requirement – Test	Result – Remark	Verdic
			_
	momentary make-before-break operation, shall		
	meet all the requirements of this clause regardless of the duration of paralleling.		
4.1.5	Inadvertent energization of the Area EPS		Р
4.1.3	The DR shall not energize the Area EPS when		P
	the Area EPS is de-energized.		F
4.1.6	Monitoring provisions	<u> </u>	N/A
4.1.0	Each DR unit of 250 kVA or more or DR aggregate	This unit output is less than	N/A
	of 250 kVA or more at a single PCC shall have	250kVA.	14//
	provisions for monitoring its connection status, real		
	power output, reactive power output, and voltage at		
	the point of DR connection.		
4.1.7	Isolation device		N/A
	When required by the Area EPS operating practices,		N/A
	a readily accessible, lockable, visible-break isolation		
	device shall be located between the Area EPS and		
	the DR unit.		
4.1.8	Interconnect integrity		P
4.1.8.1	Protection from electromagnetic interference	Τ=	P
	The interconnection system shall have the capability	The interconnection system	Р
	to withstand electromagnetic interference (EMI)	have the capability to	
	environments in accordance with IEEE Std C37.90.2-1995. The influence of EMI shall not result in a	withstand electromagnetic interference (EMI).	
	change in state or misoperation of the interconnection	` ,	
	system.		
4.1.8.2	Surge withstand performance	I .	Р
7111012	The interconnection system shall have the capability		P
	to withstand voltage and current surges in		
	accordance with the environments defined in IEEE		
	Std C62.41.2-2002 or IEEE Std C37.90.1-2002 as		
	applicable.		
4.1.8.3	Paralleling device		P
	The interconnection system paralleling-device shall		Р
	be capable of withstanding 220% of the		
	interconnection system rated voltage.		
4.2	Response to Area EPS abnormal conditions	T5	P
	Abnormal conditions can arise on the Area EPS that	Response contributed to the	Р
	require a response from the connected DR. This	safety of utility maintenance	
	response contributes to the safety of utility maintenance personnel and the general public, as well as the	personnel and the general public as well as the	
	avoidance of damage to connected equipment, including	avoidance of damage to	
	the DR. All voltage and frequency parameters	connected equipment.	
	specified in these subclauses shall be met at the PCC,	connected equipment.	
	unless otherwise stated.		
4.2.1	Area EPS faults	1	Р
· =	The DR unit shall cease to energize the Area EPS	The unit ceased to energize	Р
	for faults on the Area EPS circuit to which it is	the Area EPS.	
	connected.		
4.2.2	Area EPS reclosing coordination		Р
	The DR shall cease to energize the Area EPS circuit to		Р



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	IEEE1547		
Clause	Requirement – Test	Result – Remark	Verdict
			T
	which it is connected prior to reclosure by the Area		

	which it is connected prior	to reclosure by	the Area			
	EPS.	12 120.30 a.o by				
4.2.3	Voltage				Р	
	When any voltage is in a range given in Table 1, the DR shall cease to energize the Area EPS within the clearing time as indicated. Under mutual agreement between the EPS and DR operators, other static or dynamic voltage and clearing time trip settings shall be permitted. Clearing time is the time between the start of the abnormal condition and the DR ceasing to energize the Area EPS. For DR less than or equal to 30 kW 300 W in peak capacity, the voltage set points and clearing times shall be either fixed or field adjustable. The protection functions of the interconnection system detected the effective of fundamental frequency value of each phase to phase voltage.					
	a) The aggregate capacto a single PCC is less t				N/A	
	b) The interconnection equipment is certified to pass a non-islanding test for the system to which it is to be connected,					
	c) The aggregate DR capacity is less than 50% of the total Local EPS minimum annual integrated electrical demand for a 15 minute time period, and export of real or reactive power by the DR to the Area EPS is not permitted.					
	Table 1—Intercor	Table 1—Interconnection system default response to abnormal voltages				
	Default sett	ings ^a				
	Voltage range (% of base voltage ^b)	Clearing time (s)		adjustable up to and cluding (s)		
	$V < 45$ $45 \le V < 60$ $60 \le V < 88$ $110 < V < 120$	0.16 1 2 1		0.16 11 21 13		
	$V \ge 120$ 0.16 0.16 a Under mutual agreement between the EPS and DR operators, other static or dynamic voltage and clearing time trip settings shall be permitted b Base voltages are the nominal system voltages stated in ANSI C84.1-2011, Table 1.					
4.2.4	Frequency				Р	
	When the system freque Table 2, the DR shall ce within the a pre-set clear mutual agreement between operators, other static or clearing time trip settings time is the time between	Complied with Table 2.	P			



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			II	EEE1547			
Clause	Requirement – Test Result – Remark				Verdict		
	EPS.						
				Table 2 shall be	•		Р
	field adjustab						
	and over-free coordinated v						
				be coordinated			
	with load she						
	As mutually a						N/A
	operators, D						
				of frequency in			
				OF1, and OF2.			
			all be specifi	ied when this			
	function is pro						
	Table 2—Inte	rconnection s	system defau	alt response to a	bnormal frequenc	ies	Р
		Default	settings	Ranges of	adjustability	1	
	Function	Frequency	Clearing	Frequency	Clearing time (s)	1	
	runction	(Hz)	time	(Hz)	adjustable up to and		
	UF1	< 57	(s) 0.16	56 – 60	including 10	1	
	UF2	< 59.5	2	56 - 60	300	1	
	OF1	> 60.5	2	60 – 64	300		
	OF2	> 62	0.16	60 – 64	10]	
4.2.5	Loss of synchronism					N/A	
	Loss of synchronism protection is not required						N/A
	except as ne						
4.2.6	Reconnection				T		Р
	After an Area EPS disturbance, no DR reconnection						Р
	shall take place until the Area EPS voltage is within						
	Range B of ANSI C84.1-1995, Table 1, and frequency						
	range of 59.3 Hz to 60.5Hz. The DR interconnection system shall include an						Р
				re minutes)that			Г
	may delay re	•	,	,			
				frequency are			
	restored to t		entified above	Э.			
4.3	Power quality						Р
4.3.1	Limitation of c						P
	The DR and i						Р
	inject dc current greater than 0.5% of the full rated output current at the point of DR connection.						
4.3.2				connection.			Р
7.3.2	Limitation of flicker induced by the DR The DR shall not create objectionable flicker for other					P	
	customers on the Area EPS					'	
4.3.3	Harmonics						Р
	When the DR is serving balanced linear loads, Complied with specified Table						P
	harmonic cur	rent injection	into the Area	a EPS at	3.		
	the PCC sha						
	in Table 3. Th						
	be exclusive						
	harmonic volt	age distortion	n present in	ine Area			



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Clause	Requirement – Test	Result – Remark	Verdict

	EPS without the DR connec	ted.					
	Table 3—Maximum ha	rmonic current dis	tortion in perc	ent of curren	t (I) ^a		Р
	Individual harmonic order h (odd harmonics) ^b	i h < 17	23 ≤ h < 35	35 ≤ h	Total demand distortion (TDD)		
	Percent (%) 4.0	2.0 1.5	0.6	0.3	5.0		
	 a I = the greater of the Local EPS maxin or the DR unit rated current capacity (to PCC). bEven harmonics are limited to 25% of the second control of t	ansformed to the PCC wi	nen a transformer e				
4.4	Islanding						Р
4.4.1	Unintentional islanding						Р
	For an unintentional island in a portion of the Area EPS to DR interconnection system and cease to energize the Asseconds of the formation of	hrough the PCC shall detect the area EPS within	, the island	detected the	onnection syne island are the Area lds.	nd cease	Р
4.4.2	Intentional islanding		•				N/A
	This topic is under consider	ation for future r	evisions of t	this standar	d.		N/A
5	Interconnection test specif						Р
	This clause provides the test system meets the requiremented for all interconnect documented.	ents of Clause 4	. The applica	able tests fi	om this cla	use are	Р
	The stated test specification interconnection of DR include power inverters/converters,	ing synchronous	s machines,	induction m	nachines, o	r static	Р
5.1	Design test						Р
	This design test shall be performed as applicable to the specific interconnection system technology. The test shall be performed on a representative sample, either in the factory, at a testing laboratory, or on equipment in the field.			Р			
	This test applies to a packa system using embedded co- interconnection system that discrete components.	ged interconnec	tion an	Considere			Р
	The design test shall be cor sample in the sequence of		ame	The design conducted 4.	n test was according	to Table	Р



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	IEEE1547		
Clause	Requirement – Test	Result – Remark	Verdict

Required order Design test clause and title 1 5.11 Response to abnormal voltage and frequency 2 5.12 Synchronization 3 5.13 Intercement integrity test Suggested order 4 5.11 Response to abnormal voltage and frequency 5 5.12 Synchronization 6 5.14 Unimenterial islanding 7 5.15 Limitation of de injection 5 5.12 Synchronization 6 5.14 Unimenterial islanding 7 5.15 Limitation of de injection 8 5.16 Hamonics 7 5.15 Limitation of de injection 8 5.14 Hamonics 7 5.15 Limitation of de injection 8 5.14 Hamonics 7 7 7 7 7 7 7 7 7		Table 4-	-Sequence for conducting design test	Р
2 5.1.2 Synchronization 3 5.1.3 Interconnect integrity test Suggested order 4 5.1.1 Response to abnormal voltage and frequency 5 5.1.2 Synchronization 6 5.1.4 Unutrational sistanding 7 5.1.5 Limitation of cit sujection 8 5.1.6 Harmonics 8 5.1.6 Harmonics 9 Fee Swhen the voltage or frequency Penergize the Area EPS when the voltage or frequency exceeds the limits as specified in 4.2.3 and 4.2.4. Interconnection systems provided with field adjustable set points shall also be tested at the minimum, midpoint, and maximum of the adjustable set point ranges. These tests shall be conducted using either the simulated utility or secondary injection method. 5.1.2 Synchronization Test results conforming to requirements of A, B, or C below are accepted as indicating compliance with the requirements of 4.1.3. The appropriate conditions to be met for specific interconnection system technology follow. A. Synchronous interconnection to an EPS, or an energized local EPS to an energized Area EPS This test shall demonstrate that at the moment of the paralleling-device closure, all three parameters in Table 5 are within the stated ranges. This test shall also demonstrate that if any of the parameters are outside of the ranges stated in the table, the paralleling-device closure, stated in the table, the paralleling-device shall not close. B. Induction interconnection Self-excited induction generators shall be tested as per A in 5.1.2. This test shall determine the maximum start-up (in-rush) current drawn by the unit. The results		Required order	Design test clause and title	
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(in-rush) current drawn by the unit. The results			supplies the province of out the	N1/A
				N/A
I shall he used along with Δrea EPS impedance				
shall be used, along with Area EPS impedance information for the proposed location, to estimate				
the starting voltage				



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Clause	Requirement – Test		Result – Remark	Verdict

	_	ation parameter limits f	•		
	Aggregate rating of DR units (kVA)	Frequency difference (\Delta f, Hz)	Voltage difference (ΔV, %)	Phase angle difference $(\Delta\Phi, ^{\circ})$	
	0 – 500	0.3	10	20	
	> 500 – 1 500	0.2	5	15	
	> 1 500 – 10 000	0.1	3	10	
	drop and verify that the requirements in 4.3.2.	unit shall not exceed the s	ynchronization requireme	ents in 4.1.3 and the flicker	
С	Inverter interconne			1	P
	An inverter-based in		•	;	Р
	fundamental voltage				
	closed shall be teste	•	•		
	synchronous interco				N1/A
	All other inverter-ba		•	9	N/A
	tested to determine				
	The results shall be impedance for the p				
	starting voltage mag				
	unit shall meet the s			3	
	and the flicker requi		Jan 011101110 111 7.110		
5.1.3	Interconnect integr				Р
5.1.3.1	Protection from EN	•			P
0.1.0.1	The interconnection		e tested in		P
	accordance with II				·
	confirm that the re				
	4.1.8.1. The influe				
	change in state or	mis-operation of	the		
	interconnection sy				
5.1.3.2	Surge withstand po			-	Р
	The interconnection		e tested for the		Р
	requirement in 4.1	.8.2 in all normal	operating		
	modes in accorda	nce with IEEE St	d C62.45-2002		
	for equipment rate			at	
	the surge withstar				
	selected test level	(s) from IEEE Sto	d C62.41.2-2002		
	Interconnection sy				
	than 1000 V shall				
	manufacturer or s				
	applicable standar				
	equipment signal		ts, use IEEE Sto	1	
F 4 2 2	C37.90.1-2002. TI	ne results			
5.1.3.3	Paralleling device	the course of the	المالحة ما معاليا		P
	A dielectric test ac	•			Р
	device shall be cor		i compliance with	'	
E 1 1	the requirements of				
5.1.4	Unintentional Islan				P
	A test or field verifi				Р
	confirm that 4.4.1		or the selected		
	method of detecting	g isolation.			



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Clause	Requirement – Test	Result – Remark	Verdict
5.1.5	Limitation of dc injection		Р
	Inverter based DR shall be tested to confirm that the DR does not inject dc current greater than prescribed limits that are listed in 4.3.1.		Р
5.1.6	Harmonics		Р
	The intent of the harmonics interconnection test is to assess that under a controlled set of conditions the DR unit meets the harmonic limits specified in 4.3.3.		Р
	The DR shall be operated in parallel with a predominantly inductive voltage source with a short circuit current capacity ISC of not less than 20 times the DR rated output current at fundamental frequency. The voltage and frequency output of the voltage source shall correspond to the rated voltage and frequency of the DR. The unloaded voltage waveform produced by the Area EPS or simulated utility voltage source shall have a total harmonic distortion (THD) less than 2.5%.		Р
	The DR shall be operated at an output test load current, IL, of 33%, 66%, and at a level as close to 100% of rated output current as practical. Use total rated-current distortion (TRD) in place of TDD. TRD is the total rms value of the sum of the current harmonics created by the DR unit operating into a linear balanced load divided by the greater of the test load current (IL) demand or the rated current capacity of the DR unit (Irated). The individual harmonic distortion and TRD of the DR output current shall be measured for the first 40 harmonics. The harmonic current injections shall be exclusive of any harmonic currents due to harmonic voltage distortion present in the Area EPS without the DR connected. The test results shall not exceed the values in 4.3.3, Table 3.	The unit has operated at an output test load 33%, 66% and at a level as close to100%	P
	As an alternative, a synchronous generator DR shall be tested to meet the requirements of 4.3.3; either after installation or while powering a balanced resistive load and isolated from any other sources. The voltage harmonics while powering a resistive load at 100% of the machine kVA rating shall not exceed the levels in Table 6. Voltage harmonics shall be measured line to line for 3-phase/3 wire systems, and line to neutral for 3-phase/4-wire		N/A
	Systems. Table 6—Maximum harmonic voltage distortion in percent of rated voltage for synchronous machines Individual harmonic order h < 11		N/A
	Percent (%) 4.0 2.0 1.5 0.6 0.3 5.0		
5.2	Production tests		N/A



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iotai Qualit	ry. Assured. Page 18 of 46	Report No. 2408010	86GZU-001
	IEEE1547		
Clause	Requirement – Test	Result – Remark	Verdict
	Each interconnection system shall be subjected to	Considered by the	N/A
	requirements of 5.1.1 and 5.1.2. Interconnection systems	manufacturer during	
	with adjustable set points shall be tested at a single set	production	
	of set points as specified by the manufacturer. This test		
	may be conducted as a factory test or may be performed as part of a commissioning test (see 5.4).		
5.3	Interconnection installation evaluation	<u> </u>	N/A
5.3.1	Grounding integration with Area EPS		N/A
<u> </u>	A system design verification shall be made to		N/A
	ensure that the requirements of 4.1.2 have been		
	met.		
5.3.2	Isolation device	•	N/A
	A system design verification shall be made to		N/A
	ensure that the requirements of 4.1.7 have been		
	met.		
5.3.3	Monitoring provisions		N/A
	A system design verification shall be made to ensure		N/A
	that the provisions for monitoring are in accordance with 4.1.6.		
5.3.4	Area EPS faults		N/A
J.J. 4	A system design verification shall be made to		N/A
	ensure that the requirements of 4.2.1 have been		14//
	met.		
5.3.5	Area EPS reclosing coordination		N/A
	A system design verification shall be made to verify		N/A
	the interconnection system is coordinated with the		
	Area EPS reclosing practices in accordance with		
- 4	4.2.2.		N1/A
5.4	Commissioning tests	<u> </u>	N/A
	All commissioning tests shall be performed based on		N/A
	written test procedures.19 The following visual inspections		
	shall be performed.		
	A visual inspection shall be made to ensure that		N/A
	the grounding coordination requirement of 4.1.2 has		
	been implemented.		
	 A visual inspection shall be made to confirm the 		
	presence of the isolation device if required by 4.1.7.		
	Initial commissioning tests shall be performed on the		N/A
	installed DR and interconnection system equipment		
	prior to the initial parallel operation of the DR. The		
	following tests are required: — Operability test on the isolation device		N/A
	Unintentional-islanding functionality as specified		111/71
	in 5.4.1		
	Cease to energize functionality as specified in		
	5.4.2		
	 — Any tests of 5.1 that have not been previously 		
	performed on a representative sample and formally		
	documented		



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Clause	Requirement – Test	Result – Remark	Verdict

	— Any tests of 5.2 that have not been previously		
	performed		
	The applicable tests of 5.1 shall be repeated when:		N/A
	Functional software or firmware changes have been made on the interconnection system Any hardware component of the interconnection system has been modified in the field, or, replaced or repaired with parts different from the tested	Manufactuer has control and procedure to verify changes software or firmware.	N/A
	configuration. Sublauses 5.4.1 and 5.4.2, and the applicable tests of 5.2 shall be repeated if:		N/A
	— Protection settings have been changed after factory testing. — Protection functions have been adjusted after the initial commissioning process.		N/A
5.4.1	Unintentional islanding functionality test		N/A
5.4.1.1	Reverse-power or minimum power test		N/A
0.4.1.1	A reverse-power or minimum power test A reverse-power or minimum power function, if used to meet the requirements of 4.4.1, shall be tested using injection techniques or by adjusting the DR output and local loads to verify that the reverse power or minimum power function is met.		N/A
5.4.1.2	Non-islanding functionality test		N/A
J.4.1.2	For non-islanding interconnection systems, 5.4.2 satisfies this requirement.		N/A
5.4.1.3	Other unintentional islanding functionality tests		N/A
	If tests in 5.4.1.1 and 5.4.1.2 are not applicable to the interconnection system, the interconnection system shall be tested in accordance with procedures provided by the manufacturer or system integrator.		N/A
5.4.2	Cease to energize functionality test		N/A
	Check the cease to energize functionality by operating a load interrupting device and verify the equipment ceases to energize its output terminals and does not restart/reconnect for the required time delay. The test shall be performed on each phase individually. This test verifies conformance to the cease to energize requirement of 4.1.4, 4.2.1, 4.2.2, 4.2.3, 4.2.4, and 4.4.1.		N/A
5.5	Periodic interconnection tests		N/A
	All interconnection-related protective functions and associated batteries shall be periodically tested at intervals specified by the manufacturer, system integrator, or the authority who has jurisdiction over the DR interconnection. Periodic test reports or a log for inspection shall be maintained.		N/A

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Testing Result

4.1.8 Interconnect integrity P

Performance Criterion:

- A operate as intended during and after the test
- B operate as intended after the test
- C loss/error of function

Required Criterion: B

Test Port	Applied Voltage (kV)	Repetition Frequency (kHz)	Result
A.C. Power supply line	±4kV	2.5k	A

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Test Port	Applied Voltage (kV)	Repetition Frequency (kHz)	Result
D.C. Power supply line	±4kV	2.5k	A
External signal and control circuits	±4kV	2.5k	A

Performance Criterion:

- A operate as intended during and after the test
- B operate as intended after the test
- C loss/error of function

Required Criterion: B

Test Port	Applied Voltage (kV)	Result
A.C. Power supply line	Line to line ±6kV	A
A.C. Power supply line	line to earth ±6kV	A



5.2	Test for respo	nse to abnorr	mal voltage	conditions (25℃)		Р
Testing item	Tripping voltage/		Measured	Tripping vo	ltage/ Clear	ing time	
	Clearing time setting	Phase	1	2	3	4	5
	3	L1-N	57.13V/	57.14V/	57.15V/	57.14V/	57.15V/
		L1-1N	0.135s	0.143s	0.148s	0.146s	0.129s
Voltage -		L2-N	56.53V/	56.82V/	56.75V/	56.75V/	56.88V/
under	45%Un/	LZ IV	0.128s	0.126s	0.131s	0.139s	0.133s
(V≤45%)	0.16s	L3-N	56.49V/	56.48V/	56.49V/	56.50V/	56.69V/
(1-1070)			0.136s	0.138s	0.132s	0.139s	0.147s
		L1L2L3-N	57.11V/	57.10V/	57.12V/	57.12V/	57.13V/
			0.140s	0.139s	0.145s	0.129s	0.129s
		L1-N	57.14V/	57.10V/	57.13V/	57.15V/	57.13V/
			0.978s	0.984s	0.972s	0.983s	0.977s
		L2-N	56.54V/	56.53V/	56.52V/	56.53V/	56.53V/
	45%Un/ 1s		0.980s	0.982s	0.977s	0.990s	0.988s
		L3-N	56.28V/	56.09V/	56.10V/	56.30V/	56.30V/
		L1L2L3-N	0.988s 57.12V/	0.980s 57.11V/	0.983s 57.12V/	0.971s 57.12V/	0.974s 57.12V/
			0.982s	0.985s		0.987s	0.988s
			63.51V/	63.52V/	0.985s 63.51V/	63.54V/	63.52V/
		L1-N	5.964s	5.984s	5.980s	5.973s	5.977s
			62.97V/	62.95V/	62.95V/	62.96V/	62.96V/
Voltage -		L2-N	5.978s	5.981s	5.985s	5.986s	5.980s
under	50%Un/ 6s	101	62.71V/	62.72V/	62.55V/	62.82V/	62.65V/
(45%≤V<60%)		L3-N	5.982s	5.973s	5.983s	5.975s	5.986s
		L1L2L3-N	63.59V/	63.52V/	63.59V/	63.51V/	63.53V/
			5.974s	5.969s	5.981s	5.984s	5.973s
		L1-N	74.94V/	74.94V/	74.94V/	74.93V/	74.94V/
			10.971s	10.986s	10.976s	10.983s	10.968s
		1.0.NI	74.57V/	74.57V/	74.58V/	74.63V/	74.57V/
	500/11:/44:	L2-N	10.980s	10.969s	10.975s	10.981s	10.974s
	59%Un/ 11s	LON	74.11V/	74.13V/	74.11V/	74.11V/	74.12V/
		L3-N	10.974s	10.978s	10.967s	10.977s	10.975s
		L1L2L3-N	74.95V/	74.93V/	74.93V/	74.99V/	75.00V/
		LILZL3-IN	10.970s	10.970s	10.976s	10.980s	10.980s
		L1-N	76.05V/	76.07V/	76.03V/	76.03V/	76.05V/
		L I -IN	1.986s	1.979s	1.975s	1.966s	1.978s
		L2-N	75.86V/	75.86V/	75.87V/	75.87V/	75.87V/
	60%Un/ 2s	LZ 1 V	1.985s	1.976s	1.976s	1.978s	1.980s
	30,0011, 23	L3-N	75.74V/	75.72V/	75.62V/	75.62V/	75.61V/
Voltage -			1.981s	1.971s	1.979s	1.979s	1.983s
under		L1L2L3-N	76.09V/	76.03V/	76.02V/	76.03V/	76.04V/
(60%≤V<88%)			1.986s	1.986s	1.973s	1.973s	1.972s
`		L1-N	93.76V/	93.78V/	93.56V/	93.56V/	93.75V/
	740/11 /		11.467s	11.479s	11.475s	11.465s	11.479s
	74%Un/	L2-N	93.79V/	93.79V/	93.80V/	93.81V/	93.79V/
	11.5s		11.471s	11.471s	11.474s	11.483s	11.476s
		L3-N	93.53V/	93.60V/	93.53V/	93.53V/	93.54V/
			11.469s	11.477s	11.478s	11.483s	11.480s



Total Quality. Assured.

			93.55V/	93.74V/	93.62V/	93.55V/	93.55V/
		L1L2L3-N	11.473s	11.479s	11.469s	11.486s	11.486s
			110.09V/	110.11V/	110.07V/	110.05V/	110.07V/
		L1-N	20.975s	20.973s	20.968s	20.962s	20.974s
			109.50V/	109.69V/	109.71V/	109.70V/	109.50V/
		L2-N	20.969s	20.987s	20.982s	20.972s	20.969s
	87%Un/ 21s		109.46V/	109.33V/	109.31V/	109.44V/	109.46V/
		L3-N	20.985s	20.966s	20.970s	20.982s	20.977s
			110.25V/	110.25V/	110.32V/	110.31V/	110.26V/
		L1L2L3-N	20.981s	20.985s	20.972s	20.977s	20.980s
			140.96V/	140.95V/	140.95V/	140.96V/	140.95V/
		L1-N	0.985s	0.974s	0.983s	0.967s	0.973s
		L2-N	141.23V/	141.24V/	141.22V/	141.26V/	141.23V/
			0.969s	0.971s	0.978s	0.984s	0.967s
	111%Un/ 1s		141.38V/	141.58V/	141.57V/	141.56V/	141.57V/
		L3-N	0.969s	0.974s	0.966s	0.979s	0.978s
		14101011	140.76V/	140.83V/	140.62V/	140.56V/	140.63V/
		L1L2L3-N	0.984s	0.971s	0.978s	0.983s	0.968s
		L1-N	146.06V/	146.05V/	146.06V/	146.06V/	146.06V/
			6.981s	6.978s	6.974s	6.976s	6.971s
N 11		L2-N	146.75V/	146.74V/	146.73V/	146.73V/	146.74V/
Voltage – over	115%Un/ 7s		6.965s	6.974s	6.986s	6.977s	6.985s
(110% <v<120< td=""><td rowspan="2">L3-N</td><td>147.08V/</td><td>147.07V/</td><td>147.06V/</td><td>147.08V/</td><td>147.07V/</td></v<120<>		L3-N	147.08V/	147.07V/	147.06V/	147.08V/	147.07V/
%)			6.981s	6.970s	6.976s	6.962s	6.963s
		1.41.01.0 NI	145.86V/	145.94V/	145.89V/	145.86V/	145.86V/
		L1L2L3-N	6.980s	6.978s	6.976s	6.969s	6.989s
		14.01	151.43V/	151.36V/	151.35V/	151.36V/	151.35V/
		L1-N	12.972s	12.974s	12.966s	12.963s	12.975s
		10.0	151.84V/	151.83V/	151.84V/	151.84V/	151.85V/
	119%Un/	L2-N	12.980s	12.968s	12.984s	12.977s	12.978s
	13s	L3-N	152.17V/	152.18V/	152.17V/	152.17V/	152.18V/
		L3-IN	12.976s	12.983s	12.974s	12.986s	12.977s
		L1L2L3-N	150.96V/	150.97V/	150.96V/	150.99V/	150.96V/
		LILZL3-IN	12.976s	12.981s	12.969s	12.984s	12.976s
		1 4 NI	152.45V/	152.45V/	152.12V/	152.47V/	152.45V/
		L1-N	0.131s	0.124s	0.137s	0.133s	0.132s
		L2-N	153.05V/	153.04V/	153.04V/	153.03V/	153.05V/
Voltage – over	120%Un/	L∠-IN	0.145s	0.141s	0.144s	0.141s	0.138s
(≥120%)	0.16s	12 N	152.97V/	152.98V/	152.96V/	152.97V/	152.97V/
, ,		L3-N	0.138s	0.134s	0.139s	0.147s	0.137s
		1.41.01.0.11	152.47V/	151.94V/	152.46V/	152.49V/	152.45V/
		L1L2L3-N	0.148s	0.146s	0.135s	0.128s	0.131s



5.2	Test for respo	nse to abnorr	mal voltage	conditions (-25°C)		Р
Testing item	Tripping voltage/		Measured	Tripping vo	ltage/ Clear	ing time	
	Clearing time setting	Phase	1	2	3	4	5
		L1-N	57.13V/	57.13V/	57.14V/	57.14V/	57.12V/
		LI-IN	0.136s	0.140s	0.146s	0.137s	0.126s
Voltage -		L2-N	57.15V/	56.76V/	57.15V/	57.15V/	57.15V/
under	45%Un/		0.132s	0.139s	0.145s	0.144s	0.137s
(V≤45%)	0.16s	L3-N	56.77V/	56.53V/	56.73V/	56.74V/	56.69V/
(1-1070)			0.128s	0.135s	0.142s	0.139s	0.139s
		L1L2L3-N	56.51V/	56.50V/	56.49V/	56.59V/	56.62V/
			0.141s	0.133s	0.145s	0.132s	0.141s
		L1-N	57.14V/	57.21V/	57.19V/	57.20V/	57.13V/
			0.965s	0.976s	0.970s	0.983s	0.966s
		L2-N	56.42V/	56.30V/	56.42V/	56.29V/	56.29V/
	45%Un/ 1s		0.975s	0.973s	0.981s	0.968s	0.976s
		L3-N	56.95V/	56.94V/	57.07V/	56.97V/	56.93V/
		L1L2L3-N	0.986s 57.12V/	0.979s 57.11V/	0.990s 57.12V/	0.981s 57.12V/	0.978s 57.12V/
			0.975s	0.978s		0.979s	0.978s
			63.33V/	63.39V/	0.981s 63.33V/	63.34V/	63.32V/
		L1-N	5.973s	5.971s	5.964s	5.981s	5.970s
			62.97V/	63.33V/	63.40V/	62.96V/	63.33V/
Voltage -		L2-N	5.971s	5.977s	5.989s	5.974s	5.984s
under	50%Un/ 6s		63.32V/	63.39V/	63.32V/	63.33V/	63.36V/
(45%≤V<60%)		L3-N	5.981s	5.984s	5.980s	5.975s	5.989s
		L1L2L3-N	63.39V/	63.33V/	63.32V/	63.39V/	63.23V/
			5.984s	5.983s	5.976s	5.977s	5.981s
		L1-N	74.73V/	74.79V/	74.72V/	74.79V/	74.80V/
			10.977s	10.983s	10.970s	10.977s	10.975s
			74.80V/	74.76V/	74.77V/	74.74V/	74.97V/
		L2-N	10.975s	10.980s	10.966s	10.981s	10.981s
	59%Un/ 11s	10.11	74.93V/	74.73V/	74.80V/	74.72V/	74.72V/
		L3-N	10.984s	10.975s	10.975s	10.983s	10.981s
		1 41 01 0 N	74.95V/	74.90V/	74.83V/	74.80V/	74.90V/
		L1L2L3-N	10.979s	10.981s	10.978s	10.985s	10.983s
		1.4 NI	76.03V/	76.10V/	76.03V/	76.03V/	76.05V/
		L1-N	1.981s	1.978s	1.979s	1.976s	1.975s
		L2-N	76.05V/	76.06V/	76.11V/	75.97V/	76.07V/
	60%Un/ 2s	LZ-IN	1.972s	1.972s	1.984s	1.984s	1.977s
	00 /0011/ 25	L3-N	76.24V/	76.32V/	75.78V/	75.89V/	75.90V/
Voltage -		LO-IN	1.970s	1.981s	1.973s	1.977s	1.975s
under		L1L2L3-N	76.04V/	76.05V/	76.03V/	76.03V/	76.04V/
(60%≤V<88%)		_	1.986s	1.981s	1.975s	1.973s	1.972s
(3070=110070)		L1-N	93.75V/	93.81V/	93.56V/	93.75V/	93.74V/
		_ I I V	11.469s	11.470s	11.471s	11.477s	11.471s
	74%Un/	L2-N	93.80V/	93.73V/	93.74V/	93.83V/	93.83V/
	11.5s	I T	11.482s	11.474s	11.476s	11.484s	11.488s
		L3-N	93.73V/	93.74V/	93.73V/	93.83V/	93.74V/
			11.471s	11.481s	11.471s	11.489s	11.485s





		1410101	93.79V/	93.76V/	93.72V/	93.81V/	93.80V/
		L1L2L3-N	11.474s	11.475s	11.487s	11.485s	11.474s
		1.4.1	110.25V/	110.32V/	110.26V/	110.27V/	110.33V/
		L1-N	20.976s	20.973s	20.969s	20.977s	20.974s
		10.01	110.30V/	110.31V/	110.25V/	110.33V/	110.23V/
	070/115/046	L2-N	20.966s	20.982s	20.987s	20.983s	20.975s
	87%Un/ 21s	10.01	110.46V/	110.33V/	110.28V/	110.31V/	110.36V/
		L3-N	20.987s	20.970s	20.974s	20.965s	20.979s
		141010 N	110.25V/	110.26V/	110.31V/	110.31V/	110.26V/
		L1L2L3-N	20.965s	20.967s	20.982s	20.977s	20.970s
		1.4 NI	140.96V/	140.95V/	140.95V/	140.96V/	140.95V/
		L1-N	0.969s	0.982s	0.971s	0.969s	0.968s
		L2-N	141.23V/	141.24V/	141.22V/	141.26V/	141.23V/
	111%Un/ 1s		0.977s	0.975s	0.971s	0.968s	0.967s
		L3-N	141.38V/	141.58V/	141.57V/	141.56V/	141.57V/
		L3-IN	0.976s	0.972s	0.984s	0.980s	0.967s
		L1L2L3-N	140.76V/	140.83V/	140.62V/	140.56V/	140.63V/
			0.973s	0.969s	0.974s	0.973s	0.971s
		L1-N	146.06V/	146.05V/	146.06V/	146.06V/	146.06V/
			6.982s	6.982s	6.979s	6.974s	6.977s
Voltage over	115%Un/ 7s	L2-N	146.75V/	146.74V/	146.73V/	146.73V/	146.74V/
Voltage – over (110% <v<120< td=""><td>6.973s</td><td>6.985s</td><td>6.985s</td><td>6.974s</td><td>6.979s</td></v<120<>			6.973s	6.985s	6.985s	6.974s	6.979s
(110% <v<120 %)</v<120 		L3-N	147.08V/	147.07V/	147.06V/	147.08V/	147.07V/
70)			6.978s	6.972s	6.980s	6.984s	6.972s
		L1L2L3-N	145.86V/	145.94V/	145.89V/	145.86V/	145.86V/
		LILZL3-IN	6.978s	6.968s	6.989s	6.980s	6.983s
		L1-N	151.43V/	151.36V/	151.35V/	151.36V/	151.35V/
		LI-IN	12.972s	12.979s	12.979s	12.984s	12.982s
		L2-N	151.84V/	151.83V/	151.84V/	151.84V/	151.85V/
	119%Un/	LZ-IN	12.981s	12.979s	12.970s	12.973s	12.975s
	13s	L3-N	152.17V/	152.18V/	152.17V/	152.17V/	152.18V/
		L3-IN	12.980s	12.980s	12.971s	12.969s	12.979s
		L1L2L3-N	150.96V/	150.97V/	150.96V/	150.99V/	150.96V/
		LILZL3-IN	12.976s	12.984s	12.984s	12.998s	12.972s
		14.01	152.45V/	152.45V/	152.12V/	152.47V/	152.45V/
		L1-N	0.137s	0.128s	0.134s	0.124s	0.145s
		L2-N	153.05V/	153.04V/	153.04V/	153.03V/	153.05V/
Voltage – over	120%Un/	LZ-IN	0.142s	0.139s	0.146s	0.138s	0.133s
(≥120%)	0.16s	L3-N	152.97V/	152.98V/	152.96V/	152.97V/	152.97V/
,		L3-IN	0.136s	0.136s	0.134s	0.124s	0.133s
		1 41 01 0 N	152.47V/	151.94V/	152.46V/	152.49V/	152.45V/
		L1L2L3-N	0.143s	0.137s	0.126s	0.141s	0.139s



5.2	Test for respo	nse to abnorr	mal voltage	conditions (60℃)		Р
Testing item	Tripping voltage/		Measured	Tripping vo	ltage/ Clear	ing time	
	Clearing time setting	Phase	1	2	3	4	5
		L1-N	56.93V/	56.91V/	56.89V/	56.93V	
		LIIV	0.136s	0.141s	0.145s	0.136s	
Voltage -		L2-N	56.35V/	56.33V/	56.71V/	56.74V	
under	45%Un/		0.142s	0.141s	0.131s	0.137s	
(V≤45%)	0.16s	L3-N	56.50V/	56.48V/	56.49V/	56.29V	
(1-1070)		LOIN	0.138s	0.139s	0.146s	0.140s	
		L1L2L3-N	56.93V/	56.99V/	56.93V/	56.99V	
		L122011	0.137s	0.141s	0.148s	0.1478	
		L1-N	56.98V/	56.91V/	56.91V/	56.93V	
			0.969s	0.975s	0.973s	0.973s	
		L2-N	56.34V/	56.43V/	56.33V/	56.34V	
	45%Un/ 1s		0.986s	0.981s	0.985s	0.9759	
		L3-N	56.30V/	56.27V/	56.28V/	56.31V	
			0.982s	0.974s	0.979s	0.9789	
		L1L2L3-N	56.92V/	57.00V/	56.93V/	56.99V	
			0.984s	0.984s	0.988s	0.9769	
		L1-N	63.33V/	63.38V/	63.34V/	63.34V	
			5.974s 62.75V/	5.979s 62.74V/	5.971s 62.74V/	5.975s 62.75V	
Voltage -		L2-N	5.978s	5.977s	5.978s	5.977s	
under	50%Un/ 6s		62.70V/	62.70V/	62.71V/	62.70V	
(45%≤V<60%)		L3-N	5.984s	5.974s	5.986s	5.974s	
			63.32V/	63.39V/	63.34V/	63.40V	
		L1L2L3-N	5.978s	5.974s	5.974s	5.983s	
			74.73V/	74.79V/	74.73V/	74.72V	
		L1-N	10.979s	10.979s	10.987s	10.974	
			74.72V/	74.73V/	74.80V/	74.73V	
		L2-N	10.984s	10.986s	10.979s	10.979	
	59%Un/ 11s		74.76V/	74.81V/	74.76V/	74.73V	
		L3-N	10.974s	10.981s	10.976s	10.982	
		1.41.01.0 N	74.72V/	74.90V/	74.60V/	74.62V	
		L1L2L3-N	10.970s	10.975s	10.972s	10.977	
		14.01	76.04V/	76.10V/	76.04V/	76.02V	
		L1-N	1.981s	1.973s	1.978s	1.986s	1.979s
		L2-N	76.02V/	76.03V/	76.09V/	76.03V	// 76.03V/
	60%Un/ 2s	LZ-IN	1.967s	1.976s	1.989s	1.972s	1.980s
	00 /0011/ 23	L3-N	76.09V/	76.03V/	76.04V/	76.10V	// 76.03V/
Voltage -		L3-IN	1.984s	1.980s	1.985s	1.968s	
under		L1L2L3-N	76.04V/	76.04V/	76.04V/	76.14V	
(60%≤V<88%)		_	1.979s	1.984s	1.974s	1.973s	
(5070=1,0070)		L1-N	93.39V/	93.40V/	93.34V/	93.33V	
		LI IN	11.469s	11.478s	11.484s	11.472	
	74%Un/	L2-N	93.74V/	93.34V/	93.40V/	93.33V	
	11.5s	L2 1V	11.476s	11.471s	11.486s	11.481	
		L3-N	93.40V/	93.34V/	93.33V/	93.40V	
		2011	11.475s	11.488s	11.475s	11.475	s 11.474s



Total Quality. Assured.

			93.78V/	93.77V/	93.74V/	93.38V/	93.80V/
		L1L2L3-N	11.471s	11.470s	11.474s	11.471s	11.474s
			110.24V/	110.35V/	11.4745 110.27V/	110.43V/	11.4745 110.25V/
		L1-N	20.970s	20.981s	20.971s	20.962s	20.983s
			110.31V/	110.35V/	110.31V/	110.25V/	110.26V/
		L2-N	20.979s	20.976s	20.968s	20.982s	20.976s
	87%Un/ 21s		110.24V/	110.29V/	110.35V/	110.24V/	110.25V/
		L3-N	20.986s	20.964s	20.976s	20.973s	20.978s
			110.24V/	110.30V/	110.24V/	110.31V/	110.30V/
		L1L2L3-N	20.974s	20.979s	20.982s	20.978s	20.981s
			140.76V/	140.75V/	140.82V/	140.86V/	140.83V/
		L1-N	0.969s	0.974s	0.965s	0.964s	0.972s
			140.75V/	140.76V/	140.71V/	140.81V/	140.79V/
		L2-N	0.964s	0.973s	0.970s	0.977s	0.970s
	111%Un/ 1s		141.14V/	141.18V/	141.15V/	141.15V/	141.15V/
		L3-N	0.983s	0.969s	0.972s	0.970s	0.970s
		L1L2L3-N	141.23V/	141.25V/	141.22V/	141.22V/	141.27V/
			0.979s	0.969s	0.974s	0.963s	0.978s
			145.86V/	145.92V/	145.86V/	145.87V/	145.93V/
		L1-N	6.977s	6.978s	6.980s	6.976s	6.978s
	115%Un/ 7s	L2-N	145.88V/	145.91V/	145.94V/	145.90V/	145.92V/
Voltage – over			6.978s	6.978s	6.971s	6.968s	6.978s
(110% <v<120< td=""><td rowspan="2">L3-N</td><td>145.87V/</td><td>145.92V/</td><td>145.96V/</td><td>145.88V/</td><td>145.87V/</td></v<120<>		L3-N	145.87V/	145.92V/	145.96V/	145.88V/	145.87V/
%)			6.970s	6.978s	6.978s	6.981s	6.972s
		L1L2L3-N	145.95V/	145.94V/	145.92V/	145.88V/	145.96V/
			6.980s	6.974s	6.978s	6.970s	6.976s
		14.11	151.04V/	151.06V/	151.03V/	150.97V/	151.06V/
		L1-N	12.984s	12.976s	12.961s	12.979s	12.969s
		10.0	150.97V/	150.96V/	151.01V/	150.95V/	150.96V/
	119%Un/	L2-N	12.974s	12.978s	12.985s	12.967s	12.984s
	13s	L3-N	151.02V/	150.98V/	150.97V/	151.05V/	151.18V/
		L3-IN	12.969s	12.976s	12.986s	12.977s	12.981s
		1 41 01 2 N	150.97V/	150.99V/	151.06V/	150.99V/	150.95V/
		L1L2L3-N	12.982s	12.983s	12.966s	12.970s	12.972s
		1 4 NI	152.46V/	152.52V/	152.46V/	151.96V/	152.02V/
		L1-N	0.136s	0.135s	0.131s	0.138s	0.144s
		L2-N	152.97V/	152.84V/	152.74V/	152.83V/	152.75V/
Voltage – over	120%Un/	LZ-IN	0.141s	0.142s	0.142s	0.131s	0.129s
(≥120%)	0.16s	L3-N	152.01V/	152.95V/	152.01V/	152.96V/	152.95V/
		LO-IN	0.140s	0.136s	0.134s	0.139s	0.139s
		L1L2L3-N	152.97V/	151.95V/	152.94V/	152.04V/	152.06V/
			0.126s	0.141s	0.134s	0.141s	0.140s



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5.3	Response to	abnormal freq	uency condi	tions (25°C)			Р
Testing item		Tripping frequency/	Mea	sured Tripp	ing frequenc	cy/ Clearing	time
		Clearing time setting	1	2	3	4	5
Frequency - un	der UF1	56.00Hz/ 2s	55.990Hz/ 1.987s	55.990Hz/ 1.986s	56.000Hz/ 1.988s	55.990Hz/ 1.979s	56.000Hz/ 1.978s
Frequency - un	der UF1	58.00Hz/ 151s	57.990Hz/ 150.980s	57.990Hz/ 150.990s	57.990Hz/ 150.980s	57.990Hz/ 150.990s	57.990Hz/ 150.990s
Frequency - un	der UF1	59.50Hz/ 300s	59.490Hz/ 299.980s	59.490Hz/ 299.980s	59.490Hz/ 299.980s	59.489Hz/ 299.970s	59.490Hz/ 299.970s
Frequency - un	der UF2	56.00Hz/ 0.16s	55.990Hz/ 0.141s	55.990Hz/ 0.141s	55.990Hz/ 0.134s	55.990Hz/ 0.138s	55.990Hz/ 0.143s
Frequency - un	der UF2	58.00Hz/ 5s	57.990Hz/ 4.975s	57.990Hz/ 4.970s	57.990Hz/ 4.974s	57.990Hz/ 4.974s	57.990Hz/ 4.986s
Frequency - un	der UF2	59.50Hz/ 10s	59.499Hz/ 9.978s	59.500Hz/ 9.976s	59.499Hz/ 9.982s	59.500Hz/ 9.966s	59.500Hz/ 9.964s
Frequency - ov	er OF1	60.50Hz/ 2s	60.500Hz/ 1.973s	60.500Hz/ 1.976s	60.500Hz/ 1.972s	60.500Hz/ 1.967s	60.500Hz/ 1.984s
Frequency - ov	er OF1	62.00Hz/ 151s	62.010Hz/ 150.970s	62.010Hz/ 150.980s	62.010Hz/ 150.980s	62.010Hz/ 150.970s	62.010Hz/ 150.980s
Frequency - ov	er OF1	64.00Hz/ 300s	64.009Hz/ 299.970s	64.010Hz/ 299.970s	64.010Hz/ 299.980s	64.010Hz/ 299.980s	64.010Hz/ 299.970s
Frequency - ov	er OF2	60.50Hz/ 0.16s	60.510Hz/ 0.134s	60.510Hz/ 0.131s	60.510Hz/ 0.124s	60.510Hz/ 0.129s	60.510Hz/ 0.133s
Frequency - ov	er OF2	62.00Hz/ 5s	62.010Hz/ 4.981s	62.010Hz/ 4.966s	62.010Hz/ 4.971s	62.010Hz/ 4.983s	62.010Hz/ 4.973s
Frequency - ov	er OF2	64.00Hz/ 10s	64.010Hz/ 9.972s	64.010Hz/ 9.970s	64.010Hz/ 9.975s	64.010Hz/ 9.984s	64.010Hz/ 9.997s



5.3	Response to	abnormal freq	uency condi	itions (-25℃)		Р
Testing item		Tripping frequency/	Mea	asured Tripp	ing frequenc	cy/ Clearing	j time
		Clearing time setting	1	2	3	4	5
Frequency - u	nder UF1	56.00Hz/ 2s	55.990Hz/ 1.985s	55.990Hz/ 1.983s	55.990Hz/ 1.970s	55.990Hz 1.975s	55.990Hz/ 1.984s
Frequency - u	nder UF1	58.00Hz/ 151s	57.990Hz/ 150.970s	57.990Hz/ 150.980s	57.990Hz/ 150.980s	57.990Hz 150.980s	
Frequency - u	nder UF1	59.50Hz/ 300s	59.490Hz/ 299.980s	59.490Hz/ 299.980s	59.490Hz/ 299.980s	59.490Hz 299.970s	
Frequency - u	nder UF2	56.00Hz/ 0.16s	55.990Hz/ 0.143s	55.990Hz/ 0.147s	55.990Hz/ 0.143s	55.990Hz 0.138s	55.990Hz/ 0.134s
Frequency - u	nder UF2	58.00Hz/ 5s	57.990Hz/ 4.976s	57.990Hz/ 4.979s	57.990Hz/ 4.976s	57.990Hz 4.975s	-
Frequency - u	nder UF2	59.50Hz/ 10s	59.490Hz/ 9.967s		59.490Hz/ 9.975s	59.490Hz 9.981s	
Frequency - o	ver OF1	60.50Hz/ 2s	60.500Hz/ 1.975s	60.500Hz/ 1.977s	60.500Hz/ 1.966s	60.500Hz 1.980s	-
Frequency - o	ver OF1	62.00Hz/ 151s	62.010Hz/ 150.980s	62.010Hz/ 150.970s	62.010Hz/ 150.980s	62.010Hz 150.980s	/ 62.010Hz/
Frequency - o	ver OF1	64.00Hz/ 300s	63.995Hz/ 299.980s	63.995Hz/ 299.980s	64.010Hz/ 299.980s	63.995Hz 299.970s	
Frequency - o	ver OF2	60.50Hz/ 0.16s	60.510Hz/ 0.127s	60.510Hz/ 0.136s	60.510Hz/ 0.127s	60.510Hz 0.124s	-
Frequency - o	ver OF2	62.00Hz/ 5s	62.010Hz/ 4.978s	62.010Hz/ 4.979s	62.010Hz/ 4.966s	62.010Hz 4.981s	-
Frequency - o	ver OF2	64.00Hz/ 10s	64.010Hz/ 9.984s		64.010Hz/ 9.975s	64.010Hz 9.971s	



Total Quality. Assured.

Testing Result

5.3	Response to	abnormal freq	uency condi	itions (60°ℂ)			Р
Testing item		Tripping frequency/	Mea	asured Tripp	ing frequenc	cy/ Clearin	g time
		Clearing time setting	1	2	3	4	5
Frequency - ι	under UF1	56.00Hz/ 2s	55.990Hz/ 1.971s	55.990Hz/ 1.977s	55.990Hz/ 1.976s	56.000Hz 1.978s	z/ 55.990Hz/ 1.971s
Frequency - ι	under UF1	58.00Hz/ 151s	57.990Hz/ 150.980s	57.990Hz/ 150.970s	57.990Hz/ 150.980s	57.990Hz 150.980	
Frequency - ι	under UF1	59.50Hz/ 300s	59.490Hz/ 299.980s	59.490Hz/ 299.970s	59.490Hz/ 299.980s	59.490Hz 299.980	
Frequency - ι	under UF2	56.00Hz/ 0.16s	55.990Hz/ 0.134s	55.990Hz/ 0.133s	55.990Hz/ 0.137s	55.990Hz 0.130s	z/ 55.990Hz/ 0.135s
Frequency - ι	under UF2	58.00Hz/ 5s	57.990Hz/ 4.986s	57.990Hz/ 4.984s	57.990Hz/ 4.975s	57.990Hz 4.985s	z/ 57.990Hz/ 4.975s
Frequency - ι	under UF2	59.50Hz/ 10s	59.490Hz/ 9.972s	59.490Hz/ 9.973s	59.490Hz/ 9.966s	59.490Hz 9.971s	z/ 59.490Hz/ 9.965s
Frequency - o	over OF1	60.50Hz/ 2s	60.501Hz/ 1.981s	60.508Hz/ 1.974s	60.501Hz/ 1.974s	60.500Hz 1.976s	z/ 60.508Hz/ 1.972s
Frequency - o	over OF1	62.00Hz/ 151s	62.010Hz/ 150.970s	62.010Hz/ 150.990s	62.010Hz/ 150.970s	62.010Hz 150.980	
Frequency - o	over OF1	64.00Hz/ 300s	64.010Hz/ 299.970s	64.010Hz/ 299.970s	64.010Hz/ 299.970s	64.010Hz 299.980	
Frequency - o	over OF2	60.50Hz/ 0.16s	60.500Hz/ 0.125s	60.500Hz/ 0.126s	60.500Hz/ 0.140s	60.500Hz 0.135s	z/ 60.500Hz/ 0.128s
Frequency - o	over OF2	62.00Hz/ 5s	62.010Hz/ 4.975s	62.010Hz/ 4.965s	62.010Hz/ 4.969s	62.010Hz 4.981s	z/ 62.010Hz/ 4.973s
Frequency - o	over OF2	64.00Hz/ 10s	64.010Hz/ 9.975s	63.993Hz/ 9.967s	64.010Hz/ 9.980s	64.010Hz 9.978s	z/ 64.010Hz/ 9.970s

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5.4.4		Р		
1	2	3	4	5
4.100A	3.990A	4.119A	4.023A	4.040A
4.679A	4.603A	4.743A	4.688A	4.742A
4.071A	3.987A	3.940A	3.963A	3.840A
6	7	8	9	10
4.112A	4.065A	3.988A	4.038A	4.117A
4.750A	4.678A	4.622A	4.846A	4.868A
3.910A	3.985A	3.967A	4.076A	4.031A

5.5.3	Dielectric test	Dielectric test					
Appl	ied points:	Applied voltage:	Breakdown or f	lashover?			
Between I	nput and output	1485V	No				

5.6 DC Injec	tion for inverters without in	terconnection transformers		Р
Rated output load:	80kW	33 % of rated output load:	26	6.4kW
Output voltage:	127.12V 127.11V 127.10V	Output current (rms)	69	9.00A 9.09A 9.13A
DC current:	0.111A/0.053% 0.126A/0.060% 0.119A/0.057%	DC current limit	0.	5%In
Rated output load:	80kW	66 % of rated output load:	52	2.8kW
Output voltage:	127.17V 127.15V 127.16V	Output current (rms)	13	8.38A 8.76A 8.58A
DC current:	0.165A/0.079% 0.166A/0.079% 0.138A/0.066%	DC current limit	0.	5%In
Rated output load:	80kW	100 % of rated output load:	8	0kW
Output voltage:	127.21V 127.20V 127.23V	Output current (rms)	21	9.44A 0.08A 9.79A
DC current:	0.136A/0.065% 0.157A/0.075% 0.090A/0.043%	DC current limit	0.	5%In
Model: SUN2000-80K-	MGL0			



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5.6 DC Injec	tion for inverters without in	terconnection transformers		Р
Rated output load:	50kW	33 % of rated output load:	16	.5kW
Output voltage:	127.10V 127.14V 127.09V	Output current (rms)	43	3.33A 3.17A 3.33A
DC current:	0.210A/0.160% 0.136A/0.104% 0.269A/0.205%	DC current limit	0.5%ln	
Rated output load:	50kW	66 % of rated output load:	33	.0kW
Output voltage:	127.13V 127.16V 127.12V	Output current (rms)	86.71A 86.47A 86.54A	
DC current:	0.213A/0.162% 0.228A/0.174% 0.265A/0.202%	DC current limit	0.	5%ln
Rated output load:	50kW	100 % of rated output load:	50	.0kW
Output voltage:	127.17V 127.18V 127.16V	Output current (rms)	13	1.32A 1.00A 0.98A
DC current:	0.294A/0.224% 0.230A/0.175% 0.378A/0.288%	DC current limit	0.5%ln	
Model: SUN2000-50K-	MGL0			



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5.7.1	Unintentional islanding te	st		Р						
	Initial State with 100% Load									
	Q (VAR)	Voltage	Watt	VA						
R Load		127.02V	78.33kW							
L Load	76.46kVar	127.02V								
C Load	78.77kVar	127.02V								
	Islar	nding Test with 100%	Load	•						
Q(VAR)	Voltage	Watt	VA	Trip time (ms)						
-5%	127.02V	78.33kW		255.00						
-4%	127.02V	78.33kW		283.65						
-3%	127.02V	78.33kW		293.65						
-2%	127.02V	78.33kW		328.65						
-1%	127.02V	78.33kW		383.65						
0%	127.02V	78.33kW		545.65						
1%	127.02V	78.33kW		388.65						
2%	127.02V	78.33kW		363.65						
3%	127.02V	78.33kW		328.65						
4%	127.02V	78.33kW		313.65						
5%	127.02V	78.33kW		210.00						

Islanding Test with 100% Load								
Q(VAR)	Trip ti	1 ::4						
	the second time	the third time	Limit					
-1%	378.65	398.65	< 2 s					
0%	698.65	678.65	< 2 s					
1%	403.65	383.65	< 2 s					



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5.7.1	Unintentional islanding te	st		Р						
	Initial State with 66% Load									
	Q (VAR)	Voltage	Watt	VA						
R Load		126.96V	52.91kW							
L Load	51.68kVar	126.96V								
C Load	53.22kVar	126.96V								
	Isla	inding Test with 66%	Load							
Q(VAR)	Voltage	Watt	VA	Trip time (ms)						
-5%	126.96V	52.91kW		245.00						
-4%	126.96V	52.91kW		320.00						
-3%	126.96V	52.91kW		340.00						
-2%	126.96V	52.91kW	1	425.00						
-1%	126.96V	52.91kW	1	453.65						
0%	126.96V	52.91kW	-1	595.05						
1%	126.96V	52.91kW	1	488.65						
2%	126.96V	52.91kW		425.00						
3%	126.96V	52.91kW		345.00						
4%	126.96V	52.91kW		340.00						
5%	126.96V	52.91kW		275.00						

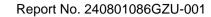
Islanding Test with 66% Load								
Q(VAR)	Trip ti	Limit						
	the second time	the third time	LIIIII					
-1%	433.65	438.65	< 2 s					
0%	658.65	658.65	< 2 s					
1%	453.65	438.65	< 2 s					



5.7.1	5.7.1 Unintentional islanding test									
	Initial State with 33% Load									
	Q (VAR)	Voltage	Watt	VA						
R Load		126.99V	25.64kW							
L Load	25.91kVar	126.99V								
C Load	26.63kVar	126.99V								
	Isla	inding Test with 33%	Load							
Q(VAR)	Voltage	Watt	VA	Trip time (ms)						
-5%	126.99V	25.64kW		265.00						
-4%	126.99V	25.64kW		275.00						
-3%	126.99V	25.64kW		321.15						
-2%	126.99V	25.64kW		328.65						
-1%	126.99V	25.64kW		335.00						
0%	126.99V	25.64kW		380.00						
1%	126.99V	25.64kW		330.00						
2%	126.99V	25.64kW		324.55						
3%	126.99V	25.64kW		313.65						
4%	126.99V	25.64kW		275.00						
5%	126.99V	25.64kW		260.00						

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Islanding Test with 33% Load								
Q(VAR)	Trip ti	l imit						
	the second time	the third time	Limit					
-1%	350.00	355.00	< 2 s					
0%	488.35	598.65	< 2 s					
1%	340.00	373.50	< 2 s					





Total Quality. Assured.

Testing Result

5.9 Open phase P								
DC input:	AC output:	Load condition:		Clearing time limit:				
415.93V	127.03V	1.30	kW		2 sec.			
1	2	3	4		5			
250ms	250ms	150ms	250ms		150ms			
L1 disconnected								
DC input:	AC output:	Load condition:		Clearin	ng time limit:			
415.96V	127.05V	1.30	kW		2 sec.			
1	2	3	4		1			
150ms	200ms	200ms	250ms		150ms			
L2 disconnected								
DC input:	AC output:	Load condition:		Clearing time limit:				
416.01V	126.99V	1.31	kW		2 sec.			
1	2	3	4		1			
200ms	250ms	150ms	250ms 150ms		150ms			
L3 disconnected								

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5.10	Reconnect follo	owing abnormal o	condition disco	onnect		Р	
DC input:		AC output:		Load condition:	Re-connec	t time setting:	
348.29V/237.9	98A/84.14kW	127.87V/211.20	.20A/80.98kW 80.98kW 300s				
Overvoltage V	erification:						
Overvoltage >	1.10Un		Does the EU	IT trip? ☑ Yes	No		
Maintain the o	vervoltage for t >	2 treconnect	Does the EU	IT reconnect? Yes	☑ No		
Step change b	ack to the V _{nomin}	al	The reconne	ct time is 305.1			
Step change b	ack to 1.10Un		Does the EU	IT reconnect? Yes	☑ No		
Additional volt	age excursion te	st	Does the EU	IT reconnect timer rese	et? ☑ Yes	☐ No	
Undervoltage	Verification:						
Undervoltage -	< 0.88Un		Does the EU	IT trip? ☑ Yes 🗌	No		
Maintain the u	ndervoltage for t	> 2 t _{reconnect}	Does the EUT reconnect? ☐ Yes ☑ No				
Step change b	ack to the V _{nomin}	al	The reconnect time is 304.7				
Step change b	ack to 0.88Un		Does the EUT reconnect? ☐ Yes ☑ No				
Additional volta	age excursion te	st	Does the EUT reconnect timer reset? ☑ Yes ☐ No				
Overfrequency			T				
Overfrequency			Does the EU	IT trip? ☑ Yes 🗌	No		
Maintain the fr	equency for $t > 2$	2 treconnect	Does the EU	IT reconnect? Yes	☑ No		
	ack to the F _{nomin}	al	The reconne	ect time is 305.3			
Step change b	ack to 62Hz		Does the EUT reconnect? ☐ Yes ☑ No				
Additional voltage excursion test Does the EUT reconne					et? ☑ Yes	☐ No	
	cy Verification:						
Underfrequence	cy < 59.5Hz		Does the EU	IT trip? ☑ Yes	No		



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Maintain the underfrequency for $t > 2$ $t_{reconnect}$	Does the EUT reconnect? ☐ Yes ☑ No
Step change back to the F _{nominal}	The reconnect time is 305.6
Step change back to 59.5Hz	Does the EUT reconnect? ☐ Yes ☑ No
Additional voltage excursion test	Does the EUT reconnect timer reset? ☑ Yes ☐ No



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5.11	Hai	Harmonics test for inverters							Р	
Load curre	ent:	<u>33</u> %	EUT rate	ed current	:: <u>209.97</u> A			DC input:_ AC output: C output cu	127.15Va	ac
Harm. order h		2	3	4	5	6	7	8	9	10
Harm. (%)	1	0.1243 0.2066 0.1578	0.0625 0.0431 0.0653	0.0730 0.0497 0.0578	0.0441 0.0406 0.0375	0.0403 0.0403 0.0369	0.0535 0.0508 0.0814	0.0388 0.0418 0.0293	0.0703 0.0747 0.0404	0.1243 0.2066 0.1578
Limit (%)	/	1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5
Harm. order h	11	12	13	14	15	16	17	18	19	20
Harm. (%)	0.0849 0.1035 0.0417	0.1909 0.1448 0.1340	0.1030 0.1047 0.0412	0.1243 0.1768 0.1092	0.0752 0.0742 0.0420	0.0507 0.0553 0.0719	0.0512 0.0539 0.0462	0.1177 0.0894 0.0580	0.0741 0.0723 0.0466	0.0727 0.0515 0.0607
Limit (%)	2.0	0.5	2.0	0.5	2.0	0.375	1.5	0.375	1.5	0.375
		l								
Harm. order h	21	22	23	24	25	26	27	28	29	30
Harm. (%)	0.0487 0.0690 0.0598	0.0613 0.0623 0.0427	0.0406 0.0509 0.0527	0.0419 0.0403 0.0337	0.0792 0.1504 0.1661	0.0474 0.0405 0.0412	0.0442 0.0507 0.0341	0.0385 0.0397 0.0263	0.1534 0.1352 0.1566	0.0377 0.0375 0.0285
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15
Harm. order h	31	32	33	34	35	36	37	38	39	40
Harm. (%)	0.0814 0.0784 0.1022	0.0239 0.0265 0.0252	0.0331 0.0304 0.0396	0.0322 0.0359 0.0211	0.1867 0.1367 0.1865	0.0296 0.0329 0.0277	0.0234 0.0457 0.0490	0.0225 0.0235 0.0215	0.0223 0.0528 0.0480	0.0297 0.0263 0.0231
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075
TRD (%)					0.4906 0.5097 0.4678					
	Limit (%)							5		
Model: SU	N2000-80	OK-MGL0								



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5.11	Hai	Harmonics test for inverters							Р		
Load current: 66 %			EUT rat	ed current	:: <u>209.97</u> A			DC input: <u>409.17</u> Vdc; AC output: <u>127.19</u> Vac AC output current: 138.37 A			
Harm. order h		2	3	4	5	6	7	8	9	10	
Harm. (%)	1	0.2209 0.2595 0.3737	0.0721 0.0713 0.0528	0.0790 0.0497 0.0884	0.0905 0.0631 0.0635	0.0469 0.0592 0.0492	0.0593 0.0547 0.0758	0.0471 0.0740 0.0436	0.0612 0.0796 0.0709	0.0544 0.1031 0.0997	
Limit (%)	/	1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5	
I I a was	T	ı	1	1	1		1		1		
Harm. order h	11	12	13	14	15	16	17	18	19	20	
Harm. (%)	0.1713 0.1578 0.2187	0.1556 0.0705 0.0992	0.2704 0.3154 0.2900	0.0934 0.1490	0.0602 0.0953 0.1360	0.0446 0.0990 0.0974	0.2251	0.1047 0.0896	0.1381 0.1695	0.0805 0.0671 0.0694	
Limit (%)	2.0	0.0992	2.0	0.0731	2.0	0.0974	0.1568 1.5	0.0625 0.375	0.1362 1.5	0.0694	
LIIIII (70)	2.0	0.5	2.0	0.5	2.0	0.373	1.5	0.373	1.5	0.373	
Harm. order h	21	22	23	24	25	26	27	28	29	30	
Harm. (%)	0.0673 0.1017 0.1188	0.0686 0.1303 0.0937	0.1115 0.0589 0.1194	0.0551 0.0690 0.0533	0.0488 0.1238 0.1129	0.0692 0.0430 0.0714	0.1206 0.0802 0.0864	0.0347 0.0479 0.0501	0.1317 0.1172 0.1511	0.0364 0.0693 0.0495	
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15	
	I.	l.		l.							
Harm. order h	31	32	33	34	35	36	37	38	39	40	
Harm. (%)	0.0574 0.0830 0.0819	0.0361 0.0411 0.0538	0.0995 0.0460 0.0752	0.0338 0.0378 0.0316	0.1745 0.1260 0.2091	0.0410 0.0516 0.0330	0.0592 0.0704 0.1026	0.0412 0.0473 0.0308	0.0422 0.0441 0.0497	0.0470 0.0377 0.0336	
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075	
TRD (%)					0.6892 0.6831 0.7586						
	Limit (%)						5				
Model: SU	N2000-80	OK-MGL0									



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5.11	5.11 Harmonics test for inverters									Р	
Load current: 100 %		<u>100</u> %	EUT rat	ed current	:: <u>209.97</u> A		DC input: 393.33Vdc; AC output: 127.20Vac AC output current: 209.20 A				
Harm. order h		2	3	4	5	6	7	8	9	10	
Harm. (%)	1	0.6366 0.3505 0.5495	0.0996 0.1052 0.0785	0.1158 0.0700 0.1006	0.1627 0.1176 0.1404	0.0558 0.0836 0.0568	0.0433 0.1065 0.1035	0.0575 0.0912 0.0567	0.1058 0.0614 0.1135	0.0969 0.0801 0.1196	
Limit (%)	/	1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5	
Harm. order h	11	12	13	14	15	16	17	18	19	20	
Harm. (%)	0.0521 0.0504 0.0510	0.0822 0.0612 0.0904	0.3447 0.3898 0.3623	0.1117 0.1869 0.1197	0.1053 0.1181 0.2095	0.1157 0.1165 0.0819	0.1772 0.0684 0.1486	0.1283 0.0786 0.0986	0.4785 0.4114 0.3836	0.1342 0.1620 0.0803	
Limit (%)	2.0	0.5	2.0	0.5	2.0	0.375	1.5	0.375	1.5	0.375	
. ,		.1		l.							
Harm. order h	21	22	23	24	25	26	27	28	29	30	
Harm. (%)	0.1767 0.0865 0.1266	0.0845 0.1308 0.1120	0.2031 0.1177 0.2071	0.1372 0.0738 0.1346	0.3328 0.1838 0.2599	0.0797 0.0689 0.0738	0.0606 0.1131 0.0974	0.0659 0.0913 0.0532	0.1356 0.1168 0.0564	0.0700 0.0608 0.0420	
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15	
	1	1	•	1	1		•		•		
Harm. order h	31	32	33	34	35	36	37	38	39	40	
Harm. (%)	0.1748 0.0962 0.1449	0.0469 0.0539 0.0617	0.0936 0.1195 0.1347	0.0436 0.0519 0.0340	0.0941 0.0926 0.0584	0.0509 0.0519 0.0375	0.0658 0.0657 0.0571	0.0632 0.0792 0.0393	0.0726 0.1183 0.1100	0.0403 0.0399 0.0274	
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075	
TRD (%)							1.1228 0.8967 1.0105				
	Limit (%)						5				
Model: SU	Model: SUN2000-80K-MGL0										



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5.11 Harmonics test for inverters									Р			
Load current: 33 %			EUT rated current: 131.23A				DC input: 417.53Vdc; AC output: 127.14Vac AC output current: 43.15 A					
Harm. order h		2	3	4	5	6	7	8	9	10		
Harm. (%)	1	0.1682 0.2225 0.1588	0.0754 0.0625 0.0878	0.0726 0.0668 0.0857	0.0629 0.0707 0.0694	0.0764 0.0649 0.0845	0.0924 0.0768 0.1007	0.0504 0.0526 0.0586	0.0591 0.0675 0.0820	0.1073 0.1147 0.0718		
Limit (%)	/	1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5		
Harm. order h	11	12	13	14	15	16	17	18	19	20		
Harm. (%)	0.2901 0.2621 0.1490	0.1773 0.1589 0.0819	0.1971 0.2221 0.1217	0.0941 0.1060 0.0825	0.0819 0.0906 0.1043	0.0892 0.1055 0.0920	0.1352 0.1392 0.1256	0.0900 0.0959 0.1043	0.1106 0.0927 0.1071	0.0911 0.0862 0.1018		
Limit (%)	2.0	0.5	2.0	0.5	2.0	0.375	1.5	0.375	1.5	0.375		
, ,		l.		l .								
Harm. order h	21	22	23	24	25	26	27	28	29	30		
Harm. (%)	0.0778 0.0969 0.1072	0.0735 0.0762 0.0883	0.0843 0.0786 0.1167	0.0801 0.0847 0.0782	0.1725 0.2754 0.1821	0.0643 0.0626 0.0732	0.0634 0.0670 0.0867	0.0631 0.0580 0.0564	0.2661 0.2086 0.2234	0.0643 0.0606 0.0514		
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15		
							•		•			
Harm. order h	31	32	33	34	35	36	37	38	39	40		
Harm. (%)	0.1302 0.1237 0.1113	0.0466 0.0516 0.0546	0.0436 0.0973 0.0998	0.0411 0.0503 0.0420	0.2835 0.2559 0.2419	0.0405 0.0453 0.0439	0.0763 0.0492 0.0646	0.0516 0.0485 0.0432	0.0658 0.0937 0.0733	0.0383 0.0420 0.0391		
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075		
TRD (%)						0.4680 0.4793 0.4133						
	Limit (%)							5				
Model: SU	Model: SUN2000-50K-MGL0											



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5.11 Harmonics test for inverters										Р	
5.11											
Load current: 66 %		<u>66</u> %	EUT rated current: <u>131.23</u> A				DC input: <u>409.33</u> Vdc; AC output: <u>127.16</u> Vac AC output current: <u>86.41</u> A				
Harm. order h		2	3	4	5	6	7	8	9	10	
Harm. (%)	1	0.1524 0.3484 0.3385	0.0835 0.0651 0.0833	0.1210 0.0844 0.0851	0.0872 0.0813 0.0775	0.0733 0.0799 0.0759	0.0925 0.0950 0.1351	0.0713 0.0620 0.0713	0.0790 0.1112 0.0789	0.1361 0.1881 0.0820	
Limit (%)		1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5	
Harm. order h	11	12	13	14	15	16	17	18	19	20	
Harm.	0.3000	0.2391	0.2806	0.1202	0.1121	0.0967	0.1637	0.1006	0.1361	0.1018	
(%)	0.2680	0.1552	0.3824	0.2178	0.0974	0.0897	0.1814	0.1108	0.1130	0.0967	
(70)	0.2276	0.1362	0.2818	0.1298	0.1113	0.0786	0.1462	0.0941	0.1052	0.1014	
Limit (%)	2.0	0.5	2.0	0.5	2.0	0.375	1.5	0.375	1.5	0.375	
Harm. order h	21	22	23	24	25	26	27	28	29	30	
Harm.	0.0910	0.0978	0.0811	0.0757	0.1321	0.0807	0.1009	0.0615	0.1714	0.0505	
(%)	0.1283	0.1048	0.1006	0.0921	0.1952	0.0667	0.1215	0.0720	0.1439	0.0508	
(70)	0.1165	0.0910	0.0926	0.0933	0.2083	0.1083	0.1693	0.0615	0.2079	0.0537	
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15	
Harm. order h	31	32	33	34	35	36	37	38	39	40	
Home	0.1181	0.0465	0.0563	0.0546	0.2666	0.0411	0.1004	0.0581	0.0540	0.0564	
Harm.	0.1643	0.0654	0.0769	0.0524	0.2701	0.0401	0.0966	0.0584	0.0715	0.0480	
(%)	0.2093	0.0877	0.0974	0.0435	0.3382	0.0439	0.1205	0.0582	0.0692	0.0446	
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075	
TRD (%)						0.4995 0.5753 0.5556					
	Limit (%)						5				
Model: SU	Model: SUN2000-50K-MGL0										



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5.11 Harmonics test for inverters									Р			
Load current: 100 %			EUT rated current: 131.23A				DC input: <u>393.75</u> Vdc; AC output: <u>127.18</u> Vac AC output current: <u>131.06</u> A					
Harm. order h		2	3	4	5	6	7	8	9	10		
Harm. (%)	1	0.3003 0.3394 0.5223	0.1018 0.0908 0.0699	0.1296 0.0885 0.0926	0.1359 0.1155 0.1079	0.0841 0.0712 0.0625	0.1029 0.0889 0.1066	0.0534 0.0850 0.0619	0.0483 0.0685 0.0598	0.0841 0.0821 0.0676		
Limit (%)	/	1.0	4.0	1.0	4.0	1.0	4.0	1.0	4.0	0.5		
	1			Т	1							
Harm. order h	11	12	13	14	15	16	17	18	19	20		
Harm.	0.1227	0.2256	0.4684	0.1008	0.0748	0.0731	0.1982	0.2384	0.4191	0.1612		
(%)	0.1627	0.1364	0.5234	0.2230	0.1278	0.0986	0.2224	0.1909	0.3414	0.1868		
` ′	0.1255	0.1090	0.4428	0.1569	0.1524	0.1029	0.1958	0.1291	0.2678	0.1003		
Limit (%)	2.0	0.5	2.0	0.5	2.0	0.375	1.5	0.375	1.5	0.375		
	ı			T								
Harm. order h	21	22	23	24	25	26	27	28	29	30		
Harm.	0.1001	0.1083	0.1488	0.1363	0.1515	0.0893	0.1010	0.0786	0.0706	0.0493		
(%)	0.0867	0.1469	0.1142	0.1425	0.1331	0.0790	0.1802	0.0899	0.0714	0.0595		
. ,	0.1128	0.1042	0.1880	0.0727	0.1113	0.1022	0.1418	0.0584	0.0594	0.0679		
Limit (%)	1.5	0.15	0.6	0.15	0.6	0.15	0.6	0.15	0.6	0.15		
	1	_	T	I	1							
Harm. order h	31	32	33	34	35	36	37	38	39	40		
Harm.	0.0493	0.0587	0.0714	0.0358	0.0743	0.0377	0.0719	0.0677	0.0730	0.0554		
(%)	0.0672	0.0726	0.1412	0.0554	0.1374	0.0514	0.0712	0.0636	0.0870	0.0405		
` ′	0.0569	0.0660	0.0952	0.0557	0.1317	0.0502	0.0638	0.0764	0.0474	0.0641		
Limit (%)	0.6	0.15	0.6	0.075	0.3	0.075	0.3	0.075	0.3	0.075		
TRD (%)						0.6009 0.6302 0.5990						
	Limit (%)							5				
Model: SU	Model: SUN2000-50K-MGL0											



Appendix 1: Photos



Overview



Left view



Total Quality. Assured.

Appendix 1: Photos

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Top view



Bottom view



Appendix 1: Photos



Terminal view



Back view



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Internal view-1

Internal view-2

(End of Report)